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| Notice of References Cited | Application/Control No. 10/790,685 | | Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL. | |
| | Examiner Phuongchi Nguyen | | Art Unit 2833 | Page 1 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| | A | US-6,386,925 | 05-2002 | Sato et al. | 439/701 |
| | B | US-5,669,788 | 09-1997 | Brockman, David J. | 439/511 |
| | C | US-6,573,453 | 06-2003 | Takada et al. | 174/72A |
| | D | US-6,666,729 | 12-2003 | Takamura et al. | 439/723 |
| | E | US-6,780,069 | 08-2004 | Scherer et al. | 439/752 |
| | F | US-6,730,057 | 05-2004 | Zhao et al. | 604/11 |
| | G | US-6,478,624 | 11-2002 | Ramey et al. | 439/608 |
| | H | US-6,461,201 | 10-2002 | Maeda et al. | 439/701 |
| | I | US-6,375,518 | 04-2002 | Sato, Kei | 439/701 |
| | J | US-6,354,887 | 03-2002 | Maeda, Akira | 439/701 |
| | K | US-6,343,960 | 02-2002 | Sato, Kei | 439/701 |
| | L | US-6,332,811 | 12-2001 | Sato, Kei | 439/701 |
| | M | US-6,319,071 | 11-2001 | Sato, Kei | 439/701 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/790,685 | Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL. | |
| | Examiner Phuongchi Nguyen | Art Unit 2833 | Page 2 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-6,146,213 | 11-2000 | Yoon, Heung-Sik | 439/716 |
| | B | US-6,645,003 | 11-2003 | Yoshida et al. | 439/507 |
| | C | US-6,551,119 | 04-2003 | Sakamoto et al. | 439/287 |
| | D | US-5,545,055 | 08-1996 | Tanaka et al. | 439/507 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
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NON-PATENT DOCUMENTS

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